

AUTOMOTIVE GRADE

AUIRFR3806

HEXFET® Power MOSFET

Features

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dV/dT Rating
- 175°C Operating Temperature
- Fast Switching

Description

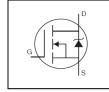
Repetitive Avalanche Allowed up to Timax

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to

achieve extremely low on-resistance per silicon area. Additional

features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide

- · Lead-Free, RoHS Compliant
- Automotive Qualified *



V_{DSS}		60V
R _{DS(on)}	typ.	12.6m Ω
	max.	15.8mΩ
I _D		43A



G	D	S
Gate	Drain	Source

Door want normalism	Dookogo Typo	Standard Pack		Orderable Bout Number
Base part number	Package Type	Form	Quantity	Orderable Part Number

Base part number Package Type Form Quantity Orderable Part Number AUIRFR3806 D-Pak Tube 75 AUIRFR3806 Tape and Reel Left 3000 AUIRFR3806TRL

Absolute Maximum Ratings

variety of other applications.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	43	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	31	Α
I _{DM}	Pulsed Drain Current ①	170	
P _D @T _C = 25°C	Maximum Power Dissipation	71	W
	Linear Derating Factor	0.47	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	73	mJ
I _{AR}	Avalanche Current ①	25	А
E _{AR}	Repetitive Avalanche Energy ①	7.1	mJ
dv/dt	Pead Diode Recovery dv/dt③	24	V/ns
T_J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol Parameter		Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		2.12	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ∅		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient ⑦		110	

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2015-11-23

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.075		V/°C	Reference to 25°C, I _D = 5mA ①
R _{DS(on)}	Static Drain-to-Source On-Resistance		12.6	15.8	mΩ	V _{GS} = 10V, I _D = 25A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 50\mu A$
gfs	Forward Trans conductance	41			S	$V_{DS} = 10V, I_{D} = 25A$
R _{G(Int)}	Internal Gate Resistance		0.79		Ω	
1	Drain-to-Source Leakage Current			20	μA	$V_{DS} = 60V, V_{GS} = 0V$
IDSS	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 48V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
IGSS	Gate-to-Source Reverse Leakage			-100	ПА	$V_{GS} = -20V$

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

• • • • • • • • • • • • • • • • • • • •		•	•		
Total Gate Charge		22	30		I _D = 25A
Gate-to-Source Charge		5.0		200	$V_{DS} = 30V$
Gate-to-Drain Charge		6.3		IIC	V _{GS} = 10V@
Total Gate Charge Sync. (Q _g - Q _{gd})		28.3			
Turn-On Delay Time		6.3			$V_{DD} = 39V$
Rise Time		40		20	I _D = 25A
Turn-Off Delay Time		49		118	$R_G = 20\Omega$
Fall Time		47			V _{GS} = 10V4
Input Capacitance		1150			$V_{GS} = 0V$
Output Capacitance		130			$V_{DS} = 50V$
Reverse Transfer Capacitance		67		рF	f = 1.0MHz
Effective Output Capacitance (Energy Related)		190			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 48V $
Effective Output Capacitance (Time Related)		230			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 48V $
	Gate-to-Source Charge Gate-to-Drain Charge Total Gate Charge Sync. (Q _q - Q _{qd}) Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance Reverse Transfer Capacitance Effective Output Capacitance (Energy Related)	Gate-to-Source Charge ————————————————————————————————————	Gate-to-Source Charge — 5.0 Gate-to-Drain Charge — 6.3 Total Gate Charge Sync. (Q _q - Q _{qd}) — 28.3 Turn-On Delay Time — 6.3 Rise Time — 40 Turn-Off Delay Time — 47 Fall Time — 47 Input Capacitance — 1150 Output Capacitance — 130 Reverse Transfer Capacitance — 67 Effective Output Capacitance (Energy Related) — 190	Gate-to-Source Charge — 5.0 — Gate-to-Drain Charge — 6.3 — Total Gate Charge Sync. (Q _q - Q _{qd}) — 28.3 — Turn-On Delay Time — 6.3 — Rise Time — 40 — Turn-Off Delay Time — 49 — Fall Time — 47 — Input Capacitance — 1150 — Output Capacitance — 130 — Reverse Transfer Capacitance — 67 — Effective Output Capacitance (Energy Related) — 190 —	Gate-to-Source Charge — 5.0 — nC Gate-to-Drain Charge — 6.3 — nC Total Gate Charge Sync. (Qg - Qgd) — 28.3 — Turn-On Delay Time — 6.3 — Rise Time — 40 — Turn-Off Delay Time — 47 — Fall Time — 47 — Input Capacitance — 1150 — Output Capacitance — 130 — Reverse Transfer Capacitance — 67 — pF Effective Output Capacitance (Energy Related) — 190 —

Diode Characteristics

Diode C	blode Characteristics						
	Parameter	Min.	Тур.	Max.	Units	Co	onditions
Is	Continuous Source Current (Body Diode)			43		MOSFET sym showing the	
I _{SM}	Pulsed Source Current (Body Diode) ①			170	A	integral revers p-n junction d	
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S =$	25A,V _{GS} = 0V ④
t _{rr}	Reverse Recovery Time		22	33		T _J = 25°C	
			26	39	ns	T _J = 125°C	$V_{R} = 51V$,
Q_{rr}	Reverse Recovery Charge		17	26	nC	$T_J = 25^{\circ}C$	$I_F = 25A$
			24	36	IIC	$T_J = 125^{\circ}C$	di/dt = 100A/µs ④
			1.4		Α	$T_J = 25^{\circ}C$	
t_{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by T_{Jmax} , starting $T_J = 25$ °C, L = 0.23mH, $R_G = 25\Omega$, $I_{AS} = 25$ A, $V_{GS} = 10$ V. Part not recommended for use above this value.
- $\label{eq:loss_spectrum} \mbox{\Im} \quad I_{SD} \leq 25 \mbox{A, di/dt} \leq 1580 \mbox{A/} \mu \mbox{s, } V_{DD} \leq V_{(BR)DSS}, \ T_{J} \leq 175 \mbox{$^{\circ}$C}.$
- \circ C_{oss eff.} (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- © $C_{oss\ eff}$. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- \otimes R₀ is measured at T_J approximately 90°C.



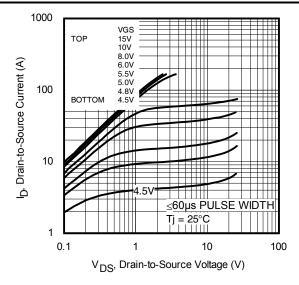


Fig. 1 Typical Output Characteristics

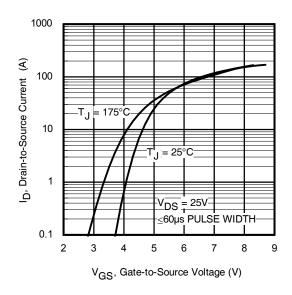


Fig. 3 Typical Transfer Characteristics

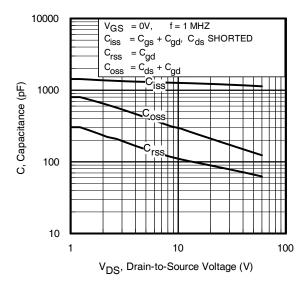


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

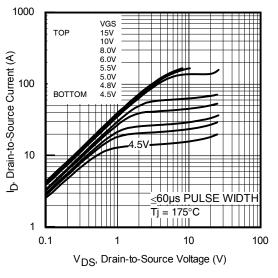


Fig. 2 Typical Output Characteristics

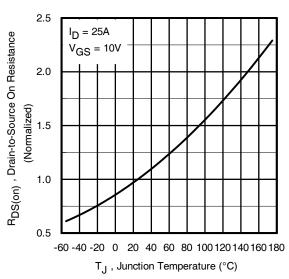


Fig. 4 Normalized On-Resistance vs. Temperature

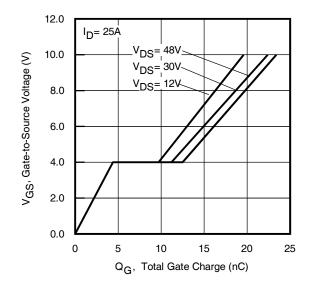
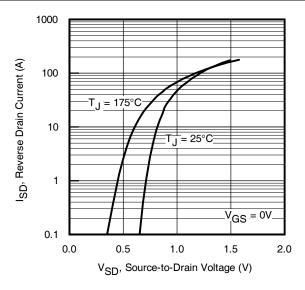


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage





OPERATION IN THIS AREA

LIMITED BY R_{DS}(on)

100

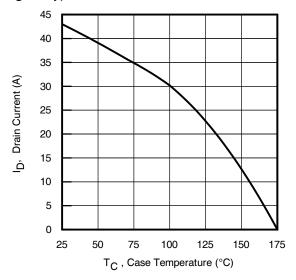
Tc = 25°C
Tj = 175°C
Single Pulse

0.1

100

V_{DS}, Drain-to-Source Voltage (V)

Fig. 7 Typical Source-to-Drain Diode Forward Voltage



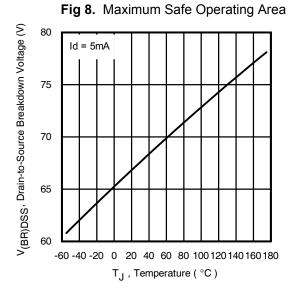


Fig. 9 Maximum Drain Current vs. Case Temperature

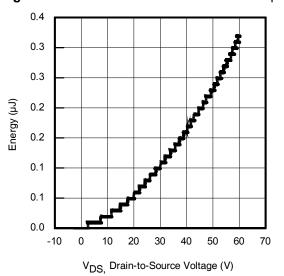


Fig. 11 Typical Coss Stored Energy

Fig 10. Drain-to-Source Breakdown Voltage

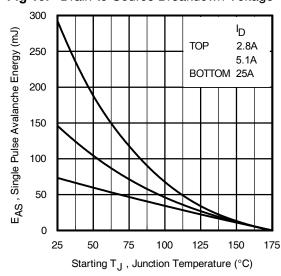


Fig 12. Maximum Avalanche Energy vs. Drain Current



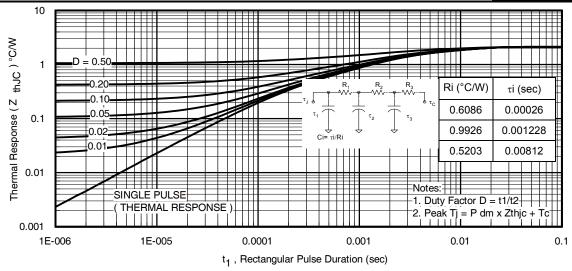


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

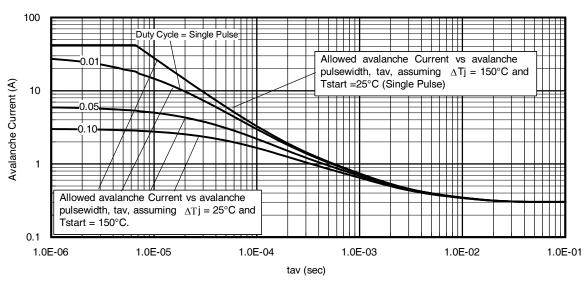


Fig 14. Typical Avalanche Current Vs. Pulse width

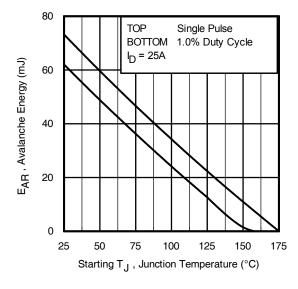


Fig 15. Maximum Avalanche Energy Vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.infineon.com)

- (For further info, see AN-1005 at www.infineon.com)

 1. Avalanche failures assumption:
 - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 13, 14).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ (} 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} = \Delta \text{T} / \text{Z}_{thJC} \\ I_{av} &= 2\Delta \text{T} / \text{ [} 1.3 \cdot \text{BV} \cdot \text{Z}_{th} \text{]} \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$



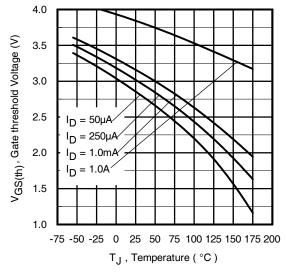


Fig 16. Threshold Voltage vs. Temperature

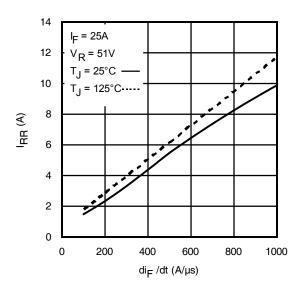


Fig. 18 - Typical Recovery Current vs. dif/dt

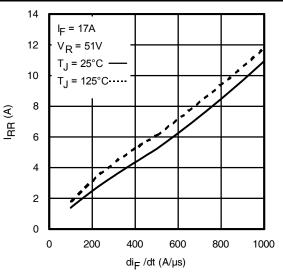


Fig. 17 - Typical Recovery Current vs. dif/dt

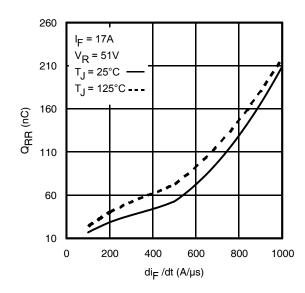


Fig. 19 - Typical Stored Charge vs. dif/dt

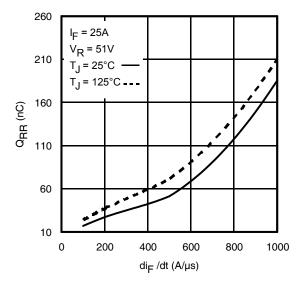


Fig. 20 - Typical Stored Charge vs. dif/dt



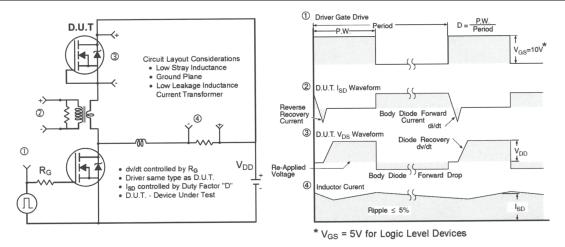


Fig 20. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

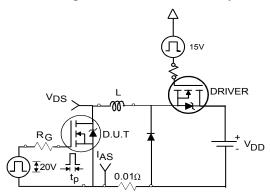


Fig 21a. Unclamped Inductive Test Circuit

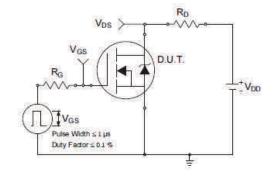


Fig 22a. Switching Time Test Circuit

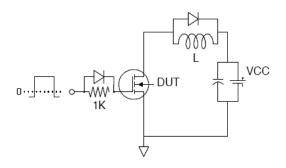


Fig 23a. Gate Charge Test Circuit

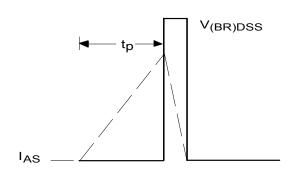


Fig 21b. Unclamped Inductive Waveforms

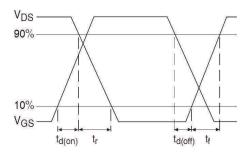


Fig 22b. Switching Time Waveforms

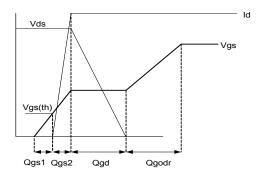
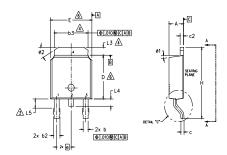


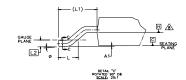
Fig 23b. Gate Charge Waveform

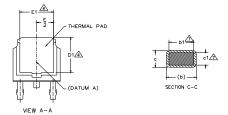


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 1 LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.— SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- bildension D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION 61 & c1 APPLIED TO BASE METAL ONLY.
- ♠ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S					N		
Y M		DIMENSIONS					
B	MILLIM	ETERS	INC	HES	O T E S		
L	MIN.	MAX.	MIN.	MAX.	S		
Α	2.18	2.39	.086	.094			
A1	-	0.13	-	.005			
b	0.64	0.89	.025	.035			
ь1	0.65	0.79	.025	.031	7		
b2	0.76	1.14	.030	.045			
b3	4.95	5.46	.195	.215	4		
С	0.46	0.61	.018	.024			
c1	0.41	0.56	.016	.022	7		
c2	0.46	0.89	.018	.035			
D	5.97	6.22	.235	.245	6		
D1	5.21	-	.205	-	4		
Ε	6.35	6.73	.250	.265	6		
E1	4.32	-	.170	-	4		
е	2.29	2.29 BSC		BSC			
Н	9.40	10.41	.370	.410			
L	1.40	1.78	.055	.070			
L1	2.74	BSC	.108	REF.			
L2	0.51	BSC	.020	BSC			
L3	0.89	1.27	.035	.050	4		
L4	-	1.02	-	.040			
L5	1.14	1.52	.045	.060	3		
ø	0.	10°	0,	10°			
ø1	0,	15*	0,	15*			
ø2	25*	35°	25*	35*			

LEAD ASSIGNMENTS

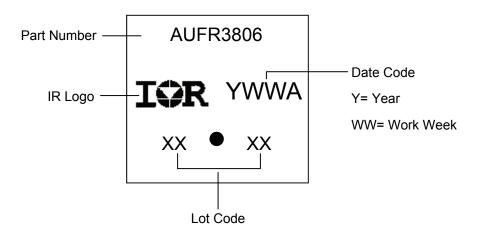
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

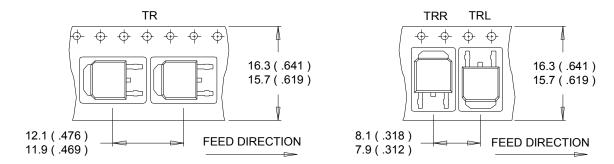
D-Pak (TO-252AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

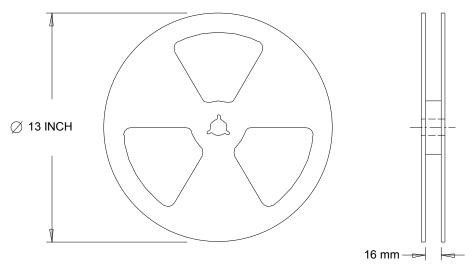


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

		Automotive				
		(per AEC-Q101)				
Qualificat	ion Level		is part number(s) passed Automotive qualification. Infineon's			
		Industrial and C	Consumer qualification level is granted by extension of the higher			
		Automotive level.				
Moisture	Moisture Sensitivity Level D-Pak MSL1					
		Class M3 (+/- 250V) [†]				
	Machine Model	AEC-Q101-002				
-00	Herea are Danke Mandal	Class H1A (+/- 500V) [†]				
ESD	Human Body Model	AEC-Q101-001				
	Observed Davis a Madal	Class C5 (+/- 2000V) [†]				
Charged Device Model		AEC-Q101-005				
RoHS Compliant		Yes				
		l				

[†] Highest passing voltage.

Revision History

Date	Comments
11/23/2015	 Updated datasheet with corporate template Corrected ordering table on page 1. Corrected typo on test condition Coss eff. V_{DS} from "60V" to "48V" on page 2. Updated typo on the fig.19 and fig.20, unit of y-axis from "A" to "nC" on page 6. Corrected typo from Rthcs to RthJA (PCB Mount) on page 1.
	Corrected typo RthJA from "62C/W" to "110C/W" on page 1.

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